Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/537,910	SHIN, HYO-SOON	
Examiner	Art Unit	
Randall Chin	1744	

SEARCHED					
Class	Subclass	Date	Examiner		
15	191.1				
15	192		V		
15	193	3/22/2006	RC		
•					
	·				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
l				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST, OCR, EPO, JPO, DERWENT		1		
Inventor name search	3/22/2006	RC		